Provisional program

9th Workshop " Combined Analysis Using X-rays, electrons and Neutron Scattering "

July 2nd - 6th, 2018, Caen (France)

Monday	Tuesday	Wednesday	Thursday	Friday
9h **Welcome Coffee !** (Eric Berthier, Daniel Chateigner)	9h **Fluorescence: XRF-GiXRF-TXRF Analysis** Including thin structures (Giancarlo Pepponi)	9h **Microstructure Analysis** size and microstrains defects Size and microstrain distributions (Luca Lutterotti)	9h **Residual Stress Analysis** Stresses, macrostress Texture and Stresses (Luca Lutterotti)	9h **Batching analyses** (Luca Lutterotti)
	~10h30 / 11h : coffe break			
10h30 **Introduction** (Daniel Chateigner) 10h40 **Instrumentations Measurements** (Henry Pillière)	**X-ray reflectivity Analysis** Specular reflectivity Fresnel, Parratt Formalisms Roughness (Giancarlo Pepponi)	**Quantitative Texture Analysis** From pole figures to ODF (Daniel Chateigner)	**Combined Analysis from images** (Luca Lutterotti)	**Rietveld-PDF** (Luca Lutterotti)
	~12h30 / 14h : Lunch			
Classical Rietveld Analysis **Phase analysis** (Luca Lutterotti)	**Practical session: XRR** **and XRF on bulk**	**Practical session** Rietveld Texture Analysis	**Practical session** Stresses of textured films	**Practical session** TEM examples
	~15h30 / 16h : coffe break			
Practical session: Rietveld analysis and Phase Quantification	**Practical session: XRD and XRF Combined Analysis**	**Practical session** Combined Phase, Texture and Microstructure	**Practical session** Stresses-texture from images	**Practical session** PDF
	~18h End of the day			
	~19h Dinner		**~19h Dinner**	

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